

ISL9V3036D3S / ISL9V3036S3S / ISL9V3036P3

EcoSPARK® 300mJ, 360V, N-Channel Ignition IGBT

General Description

The ISL9V3036D3S, ISL9V3036S3S, and ISL9V3036P3 are the next generation IGBTs that offer outstanding SCIS capability in the space saving D-Pak (TO-252), as well as the industry standard D²-Pak (TO-263) and TO-220 plastic packages. These devices are intended for use in automotive ignition circuits, specifically as a coil drivers. Internal diodes provide voltage clamping without the need for external components.

EcoSPARK® devices can be custom made to specific clamp voltages. Contact your nearest Fairchild sales office for more information

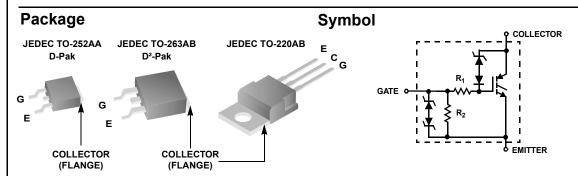
Formerly Developmental Type 49442

Applications

- · Automotive Ignition Coil Driver Circuits
- · Coil- On Plug Applications

Features

- Industry Standard D²-Pak package
- SCIS Energy = 300mJ at T_J = 25°C
- · Logic Level Gate Drive



Device Maximum Ratings $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Ratings	Units	
BV _{CER}	Collector to Emitter Breakdown Voltage (I _C = 1 mA)	360	V	
BV _{ECS}	Emitter to Collector Voltage - Reverse Battery Condition (I _C = 10 mA)	24	V	
E _{SCIS25}	$T_J = 25$ °C, $I_{SCIS} = 14.2$ A, L = 3.0 mHy	300	mJ	
E _{SCIS150}	$T_J = 150$ °C, $I_{SCIS} = 10.6A$, L = 3.0 mHy	170	mJ	
I _{C25}	Collector Current Continuous, At T _C = 25°C, See Fig 9	21	Α	
I _{C110}	Collector Current Continuous, At T _C = 110°C, See Fig 9	17	Α	
V_{GEM}	Gate to Emitter Voltage Continuous	±10	V	
P _D	Power Dissipation Total T _C = 25°C	150	W	
	Power Dissipation Derating T _C > 25°C	1.0	W/°C	
TJ	Operating Junction Temperature Range	-40 to 175	°C	
T _{STG}	Storage Junction Temperature Range	-40 to 175	°C	
TL	Max Lead Temp for Soldering (Leads at 1.6mm from Case for 10s)	300	°C	
T _{pkg}	Max Lead Temp for Soldering (Package Body for 10s)	260	°C	
ESD	Electrostatic Discharge Voltage at 100pF, 1500Ω	4	kV	

V3036D V3036S V3036P V3036D V3036S) ISL	Device 9V3036D3ST	Package	: -:						
V3036S V3036P V3036D			TO-252AA	Reel Size 330mm		Tape Width 16mm			Quantity 2500	
V3036P V3036D		9V3036S3ST	TO-263AB	330mm		24mm			800	
V3036D			TO-220AA	Tube		N/A			50	
		9V3036D3S TO-252AA		Tube		N/A			75	
		9V3036S3S	TO-263AB	Tube		N/A			50	
	<u> </u>			nless otherwise n	oted	'	1 //			
Symbol	Parameter			Test Conditions		Min	Тур	Max	Units	
ff State	Charact	eristics								
BV _{CER}	Collector to Emitter Breakdown Voltage			I_C = 2mA, V_{GE} = 0, R_G = 1K Ω , See Fig. 15 T_J = -40 to 150°C		330	360	390	V	
BV _{CES}	Collector to Emitter Breakdown Voltage			I_C = 10mA, V_{GE} = 0, R_G = 0, See Fig. 15 T_J = -40 to 150°C		350	380	410	V	
BV _{ECS}	Emitter to Collector Breakdown Voltage			$I_C = -75$ mA, $V_{GE} = 0$ V, $T_C = 25$ °C		30	-	-	V	
BV _{GES}	Gate to E	mitter Breakdo	wn Voltage	$I_{GES} = \pm 2mA$ $V_{CER} = 250V, T_C = 25^{\circ}C$		±12	±14	-	V	
I _{CER}	Collector	Collector to Emitter Leakage Current			T _C = 25°C		-	25	μΑ	
				$R_G = 1K\Omega$ See Fig. 11	T _C = 150°C	-	-	1	mA	
I _{ECS}	Emitter to Collector Leakage Current			V_{EC} = 24V, See		-	-	1	mA	
				Fig. 11	T _C = 150°C	-	-	40	mA	
R_1	Series Gate Resistance					-	70	-	Ω	
R ₂		mitter Resistar	nce			10K	-	26K	Ω	
n State	,			T					T	
$V_{CE(SAT)}$	Collector to Emitter Saturation Voltage			I _C = 6A, V _{GE} = 4V	T _C = 25°C, See Fig. 3	-	1.25	1.60	V	
\/	Collector to Emitter Saturation Voltage			$I_C = 10A$	T _C = 150°C,		1.58	1.80	V	
$V_{CE(SAT)}$				$V_{GE} = 4.5V$	See Fig. 4	_	1.50	1.00	v	
V _{CE(SAT)}	Collector	Collector to Emitter Saturation Voltage		I _C = 15A, V _{GE} = 4.5V	T _C = 150°C	-	1.90	2.20	V	
ynamic (Charact	eristics		I GE			l	ı		
$Q_{G(ON)}$	Gate Cha				I _C = 10A, V _{CE} = 12V, V _{GE} = 5V, See Fig. 14			-	nC	
V _{GE(TH)}	Gate to F	mitter Thresho	old Voltage	I _C = 1.0mA,	T _C = 25°C	1.3	-	2.2	V	
- GE(1H)			V _{CE} = V _{GE} , See Fig. 10	T _C = 150°C	0.75	-	1.8	V		
V_{GEP}	Gate to E	mitter Plateau	Voltage	I _C = 10A,	V _{CE} = 12V	-	3.0	-	V	
witching) Charac	teristics								
t _{d(ON)R}	Current 7	urn-On Delay	Time-Resistive	istive $V_{CF} = 14V$, $R_1 = 1\Omega$,		-	0.7	4	μs	
t _{rR}		Current Rise Time-Resistive			V_{GE} = 5V, R_G = 1K Ω T_J = 25°C, See Fig. 12		2.1	7	μs	
t _{d(OFF)L}	Current 7	Current Turn-Off Delay Time-Inductive		$V_{CE} = 300V, R_L = 500\mu H,$		-	4.8	15	μs	
t _{fL}	Current F	Current Fall Time-Inductive			V_{GE} = 5V, R_G = 1K Ω T _J = 25°C, See Fig. 12		2.8	15	μs	
SCIS	Self Clamped Inductive Switching			$T_J = 25^{\circ}C, L = 3.0 \text{ mH},$ $R_G = 1K\Omega, V_{GE} = 5V$		-	-	300	mJ	
hermal C	Characte	eristics								

Typical Performance Curves

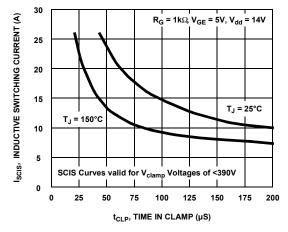


Figure 1. Self Clamped Inductive Switching Current vs Time in Clamp

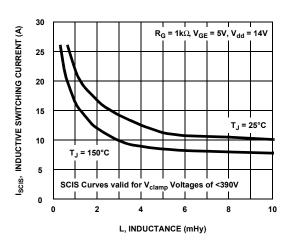


Figure 2. Self Clamped Inductive Switching Current vs Inductance

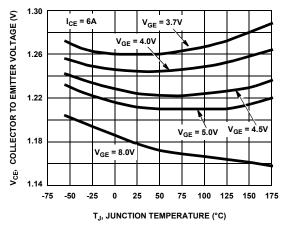


Figure 3. Collector to Emitter On-State Voltage vs Junction Temperature

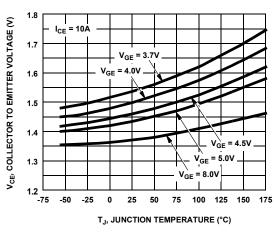


Figure 4. Collector to Emitter On-State Voltage vs Junction Temperature

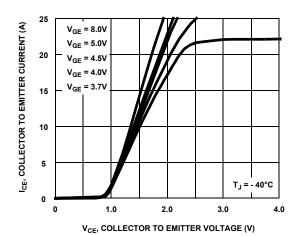


Figure 5. Collector to Emitter On-State Voltage vs Collector Current

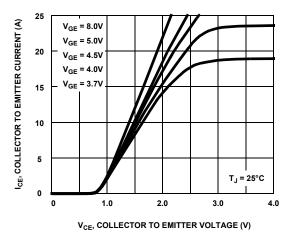


Figure 6. Collector to Emitter On-State Voltage vs Collector Current

Typical Performance Curves (Continued)

Figure 7. Collector to Emitter On-State Voltage vs Collector Current

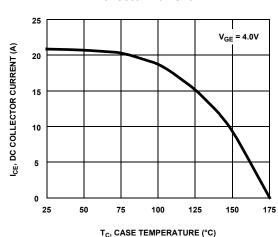


Figure 9. DC Collector Current vs Case Temperature

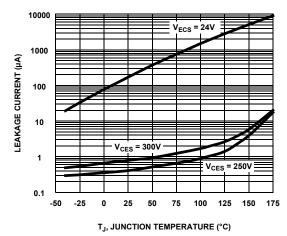


Figure 11. Leakage Current vs Junction Temperature

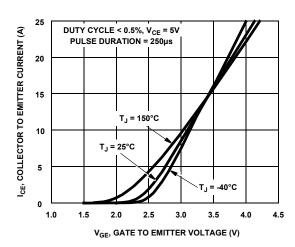


Figure 8. Transfer Characteristics

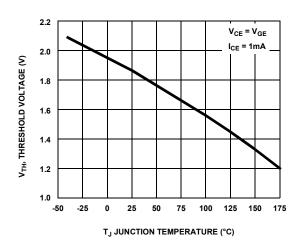


Figure 10. Threshold Voltage vs Junction Temperature

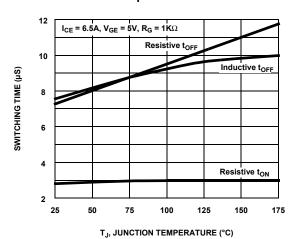


Figure 12. Switching Time vs Junction Temperature

1200 Collector to Emitter Triple 13. Capacitance vs Collector to Emitter

Typical Performance Curves (Continued)

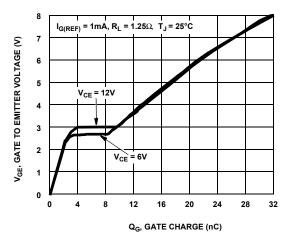


Figure 13. Capacitance vs Collector to Emitter Voltage

Figure 14. Gate Charge

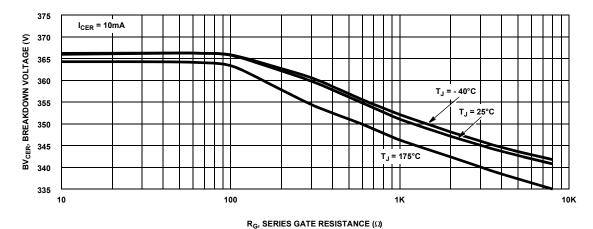


Figure 15. Breakdown Voltage vs Series Gate Resistance

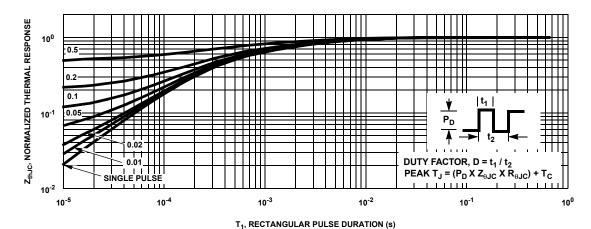
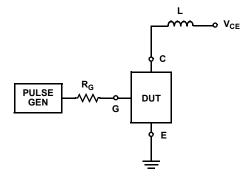


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

Test Circuit and Waveforms



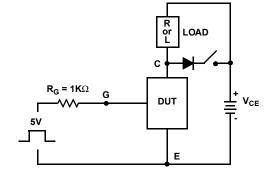
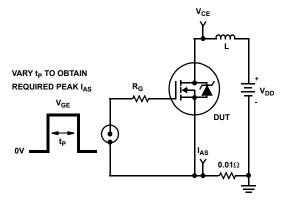


Figure 17. Inductive Switching Test Circuit

Figure 18. $t_{\rm ON}$ and $t_{\rm OFF}$ Switching Test Circuit



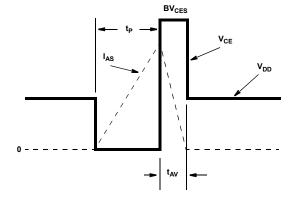
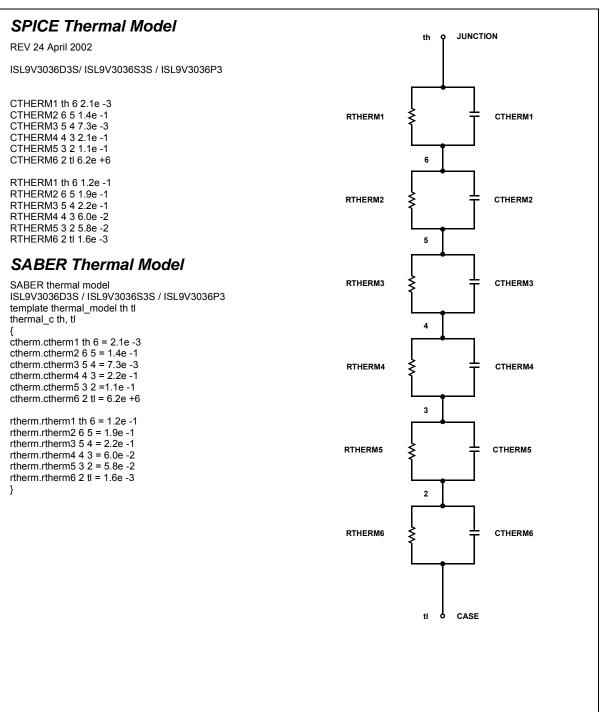


Figure 19. Unclamped Energy Test Circuit

Figure 20. Unclamped Energy Waveforms



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